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Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details

Product Status	Obsolete
Core Processor	PowerPC e300
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	533MHz
Co-Processors/DSP	Security; SEC
RAM Controllers	DDR
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100/1000Mbps (2)
SATA	-
USB	USB 2.0 + PHY (2)
Voltage - I/O	2.5V, 3.3V
Operating Temperature	0°C ~ 105°C (TA)
Security Features	Cryptography, Random Number Generator
Package / Case	672-LBGA
Supplier Device Package	672-LBGA (35x35)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mpc8347ezuajfb

2 Electrical Characteristics

This section provides the AC and DC electrical specifications and thermal characteristics for the MPC8347E. The MPC8347E is currently targeted to these specifications. Some of these specifications are independent of the I/O cell, but are included for a more complete reference. These are not purely I/O buffer design specifications.

2.1 Overall DC Electrical Characteristics

This section covers the ratings, conditions, and other characteristics.

2.1.1 Absolute Maximum Ratings

Table 1 provides the absolute maximum ratings.

Table 1. Absolute Maximum Ratings¹

Characteristic		Symbol	Max Value	Unit	Notes
Core supply voltage		V_{DD}	–0.3 to 1.32	V	
PLL supply voltage		AV_{DD}	–0.3 to 1.32	V	
DDR DRAM I/O voltage		GV_{DD}	–0.3 to 3.63	V	
Three-speed Ethernet I/O, MII management voltage		LV_{DD}	–0.3 to 3.63	V	
PCI, local bus, DUART, system control and power management, I ² C, and JTAG I/O voltage		OV_{DD}	–0.3 to 3.63	V	
Input voltage	DDR DRAM signals	MV_{IN}	–0.3 to ($GV_{DD} + 0.3$)	V	2, 5
	DDR DRAM reference	MV_{REF}	–0.3 to ($GV_{DD} + 0.3$)	V	2, 5
	Three-speed Ethernet signals	LV_{IN}	–0.3 to ($LV_{DD} + 0.3$)	V	4, 5
	Local bus, DUART, CLKIN, system control and power management, I ² C, and JTAG signals	OV_{IN}	–0.3 to ($OV_{DD} + 0.3$)	V	3, 5
	PCI	OV_{IN}	–0.3 to ($OV_{DD} + 0.3$)	V	6
Storage temperature range		T_{STG}	–55 to 150	°C	

Notes:

- ¹ Functional and tested operating conditions are given in Table 2. Absolute maximum ratings are stress ratings only, and functional operation at the maximums is not guaranteed. Stresses beyond those listed may affect device reliability or cause permanent damage to the device.
- ² **Caution:** MV_{IN} must not exceed GV_{DD} by more than 0.3 V. This limit can be exceeded for a maximum of 20 ms during power-on reset and power-down sequences.
- ³ **Caution:** OV_{IN} must not exceed OV_{DD} by more than 0.3 V. This limit can be exceeded for a maximum of 20 ms during power-on reset and power-down sequences.
- ⁴ **Caution:** LV_{IN} must not exceed LV_{DD} by more than 0.3 V. This limit can be exceeded for a maximum of 20 ms during power-on reset and power-down sequences.
- ⁵ (M,L,O) V_{IN} and MV_{REF} may overshoot/undershoot to a voltage and for a maximum duration as shown in Figure 2.
- ⁶ OV_{IN} on the PCI interface can overshoot/undershoot according to the PCI Electrical Specification for 3.3-V operation, as shown in Figure 3.

Table 16. Expected Delays for Address/Command

Load	Delay	Unit
4 devices (12 pF)	3.0	ns
9 devices (27 pF)	3.6	ns
36 devices (108 pF) + 40 pF compensation capacitor	5.0	ns
36 devices (108 pF) + 80 pF compensation capacitor	5.2	ns

Figure 14 shows the TBI receive AC timing diagram.

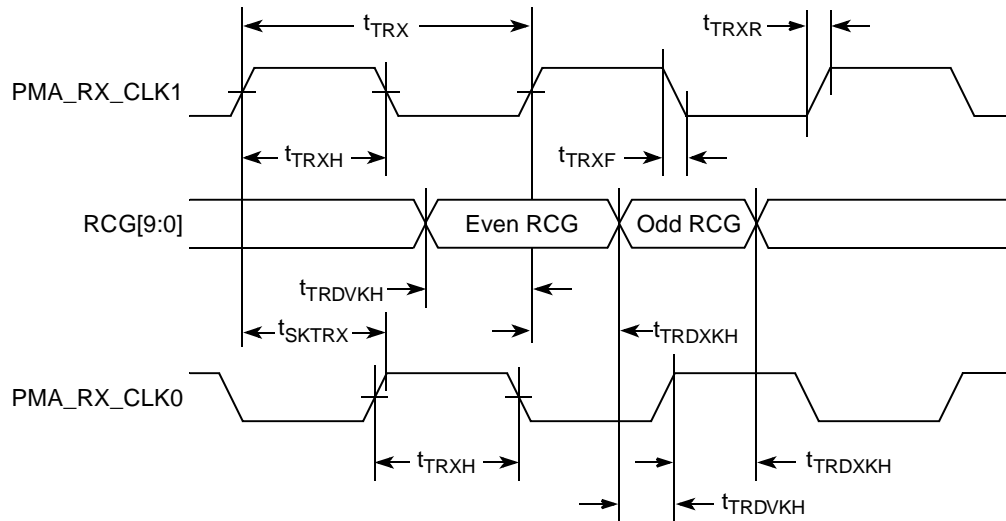


Figure 14. TBI Receive AC Timing Diagram

8.2.4 RGMII and RTBI AC Timing Specifications

Table 27 presents the RGMII and RTBI AC timing specifications.

Table 27. RGMII and RTBI AC Timing Specifications

At recommended operating conditions with V_{DD} of $2.5\text{ V} \pm 5\%$.

Parameter/Condition	Symbol ¹	Min	Typ	Max	Unit
Data to clock output skew (at transmitter)	t_{SKRGT}	-0.5	—	0.5	ns
Data to clock input skew (at receiver) ²	t_{SKRGT}	1.0	—	2.8	ns
Clock cycle duration ³	t_{RGT}	7.2	8.0	8.8	ns
Duty cycle for 1000Base-T ^{4, 5}	t_{RGTH}/t_{RGT}	45	50	55	%
Duty cycle for 10BASE-T and 100BASE-TX ^{3, 5}	t_{RGTH}/t_{RGT}	40	50	60	%
Rise time (20%–80%)	t_{RGTR}	—	—	0.75	ns
Fall time (20%–80%)	t_{RGTF}	—	—	0.75	ns
GTX_CLK125 reference clock period	t_{G12}^6	—	8.0	—	ns
GTX_CLK125 reference clock duty cycle	t_{G125H}/t_{G125}	47	—	53	%

Notes:

- In general, the clock reference symbol for this section is based on the symbols RGT to represent RGMII and RTBI timing. For example, the subscript of t_{RGT} represents the TBI (T) receive (RX) clock. Also, the notation for rise (R) and fall (F) times follows the clock symbol. For symbols representing skews, the subscript is SK followed by the clock being skewed (RGT).
- This implies that PC board design requires clocks to be routed so that an additional trace delay of greater than 1.5 ns is added to the associated clock signal.
- For 10 and 100 Mbps, t_{RGT} scales to $400\text{ ns} \pm 40\text{ ns}$ and $40\text{ ns} \pm 4\text{ ns}$, respectively.
- Duty cycle may be stretched/shrunk during speed changes or while transitioning to a received packet clock domains as long as the minimum duty cycle is not violated and stretching occurs for no more than three t_{RGT} of the lowest speed transitioned.
- Duty cycle reference is $V_{DD}/2$.
- This symbol represents the external GTX_CLK125 and does not follow the original symbol naming convention.

8.3.2 MII Management AC Electrical Specifications

Table 30 provides the MII management AC timing specifications.

Table 30. MII Management AC Timing Specifications

At recommended operating conditions with LV_{DD} is 3.3 V \pm 10% or 2.5 V \pm 5%.

Parameter/Condition	Symbol ¹	Min	Typ	Max	Unit	Notes
MDC frequency	f_{MDC}	—	2.5	—	MHz	2
MDC period	t_{MDC}	—	400	—	ns	
MDC clock pulse width high	t_{MDCH}	32	—	—	ns	
MDC to MDIO delay	t_{MDKHDx}	10	—	170	ns	3
MDIO to MDC setup time	t_{MDDVKH}	5	—	—	ns	
MDIO to MDC hold time	t_{MDDXKH}	0	—	—	ns	
MDC rise time	t_{MDCR}	—	—	10	ns	
MDC fall time	t_{MDHF}	—	—	10	ns	

Notes:

1. The symbols for timing specifications follow the pattern of $t_{(\text{first two letters of functional block})(\text{signal})(\text{state})(\text{reference})(\text{state})}$ for inputs and $t_{(\text{first two letters of functional block})(\text{reference})(\text{state})(\text{signal})(\text{state})}$ for outputs. For example, t_{MDKHDx} symbolizes management data timing (MD) for the time t_{MDC} from clock reference (K) high (H) until data outputs (D) are invalid (X) or data hold time. Also, t_{MDDVKH} symbolizes management data timing (MD) with respect to the time data input signals (D) reach the valid state (V) relative to the t_{MDC} clock reference (K) going to the high (H) state or setup time. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
2. This parameter is dependent on the csb_clk speed (that is, for a csb_clk of 267 MHz, the maximum frequency is 8.3 MHz and the minimum frequency is 1.2 MHz; for a csb_clk of 375 MHz, the maximum frequency is 11.7 MHz and the minimum frequency is 1.7 MHz).
3. This parameter is dependent on the csb_clk speed (that is, for a csb_clk of 267 MHz, the delay is 70 ns and for a csb_clk of 333 MHz, the delay is 58 ns).

Figure 16 shows the MII management AC timing diagram.

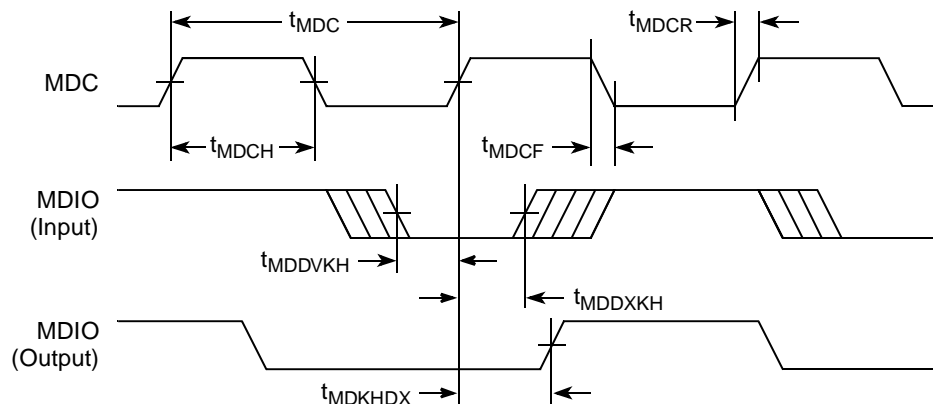


Figure 16. MII Management Interface Timing Diagram

9 USB

This section provides the AC and DC electrical specifications for the USB interface of the MPC8347E.

9.1 USB DC Electrical Characteristics

Table 31 provides the DC electrical characteristics for the USB interface.

Table 31. USB DC Electrical Characteristics

Parameter	Symbol	Min	Max	Unit
High-level input voltage	V_{IH}	2	$OV_{DD} + 0.3$	V
Low-level input voltage	V_{IL}	-0.3	0.8	V
Input current	I_{IN}	—	± 5	μA
High-level output voltage, $I_{OH} = -100 \mu A$	V_{OH}	$OV_{DD} - 0.2$	—	V
Low-level output voltage, $I_{OL} = 100 \mu A$	V_{OL}	—	0.2	V

9.2 USB AC Electrical Specifications

Table 32 describes the general timing parameters of the USB interface of the MPC8347E.

Table 32. USB General Timing Parameters (ULPI Mode Only)

Parameter	Symbol ¹	Min	Max	Unit	Notes
USB clock cycle time	t_{USCK}	15	—	ns	2–5
Input setup to USB clock—all inputs	t_{USIVKH}	4	—	ns	2–5
Input hold to USB clock—all inputs	t_{USIXKH}	1	—	ns	2–5
USB clock to output valid—all outputs	t_{USKHOV}	—	7	ns	2–5
Output hold from USB clock—all outputs	t_{USKHOX}	2	—	ns	2–5

Notes:

1. The symbols for timing specifications follow the pattern of $t_{(\text{first two letters of functional block})(\text{signal})(\text{state})(\text{reference})(\text{state})}$ for inputs and $t_{(\text{first two letters of functional block})(\text{reference})(\text{state})(\text{signal})(\text{state})}$ for outputs. For example, t_{USIXKH} symbolizes USB timing (US) for the input (I) to go invalid (X) with respect to the time the USB clock reference (K) goes high (H). Also, t_{USKHOX} symbolizes USB timing (US) for the USB clock reference (K) to go high (H), with respect to the output (O) going invalid (X) or output hold time.
2. All timings are in reference to USB clock.
3. All signals are measured from $OV_{DD}/2$ of the rising edge of the USB clock to $0.4 \times OV_{DD}$ of the signal in question for 3.3 V signaling levels.
4. Input timings are measured at the pin.
5. For active/float timing measurements, the Hi-Z or off-state is defined to be when the total current delivered through the component pin is less than or equal to that of the leakage current specification.

Table 34. Local Bus General Timing Parameters—DLL On (continued)

Parameter	Symbol ¹	Min	Max	Unit	Notes
Output hold from local bus clock for LAD/LDP	t _{LBKHOX2}	1	—	ns	3
Local bus clock to output high impedance for LAD/LDP	t _{LBKHOZ}	—	3.8	ns	8

Notes:

1. The symbols for timing specifications follow the pattern of t_{(first two letters of functional block)(signal)(state)(reference)(state)} for inputs and t_{(first two letters of functional block)(reference)(state)(signal)(state)} for outputs. For example, t_{LBIXKH1} symbolizes local bus timing (LB) for the input (I) to go invalid (X) with respect to the time the t_{LBK} clock reference (K) goes high (H), in this case for clock one (1). Also, t_{LBKHOX} symbolizes local bus timing (LB) for the t_{LBK} clock reference (K) to go high (H), with respect to the output (O) going invalid (X) or output hold time.
2. All timings are in reference to the rising edge of LSYNC_IN.
3. All signals are measured from OV_{DD}/2 of the rising edge of LSYNC_IN to 0.4 × OV_{DD} of the signal in question for 3.3 V signaling levels.
4. Input timings are measured at the pin.
5. t_{LBOTOT1} should be used when RCWH[LALE] is not set and when the load on the LALE output pin is at least 10 pF less than the load on the LAD output pins.
6. t_{LBOTOT2} should be used when RCWH[LALE] is set and when the load on the LALE output pin is at least 10 pF less than the load on the LAD output pins.
7. t_{LBOTOT3} should be used when RCWH[LALE] is set and when the load on the LALE output pin equals the load on the LAD output pins.
8. For active/float timing measurements, the Hi-Z or off-state is defined to be when the total current delivered through the component pin is less than or equal to that of the leakage current specification.

Table 35. Local Bus General Timing Parameters—DLL Bypass⁹

Parameter	Symbol ¹	Min	Max	Unit	Notes
Local bus cycle time	t _{LBK}	15	—	ns	2
Input setup to local bus clock	t _{LBIVKH}	7	—	ns	3, 4
Input hold from local bus clock	t _{LBIXKH}	1.0	—	ns	3, 4
LALE output fall to LAD output transition (LATCH hold time)	t _{LBOTOT1}	1.5	—	ns	5
LALE output fall to LAD output transition (LATCH hold time)	t _{LBOTOT2}	3	—	ns	6
LALE output fall to LAD output transition (LATCH hold time)	t _{LBOTOT3}	2.5	—	ns	7

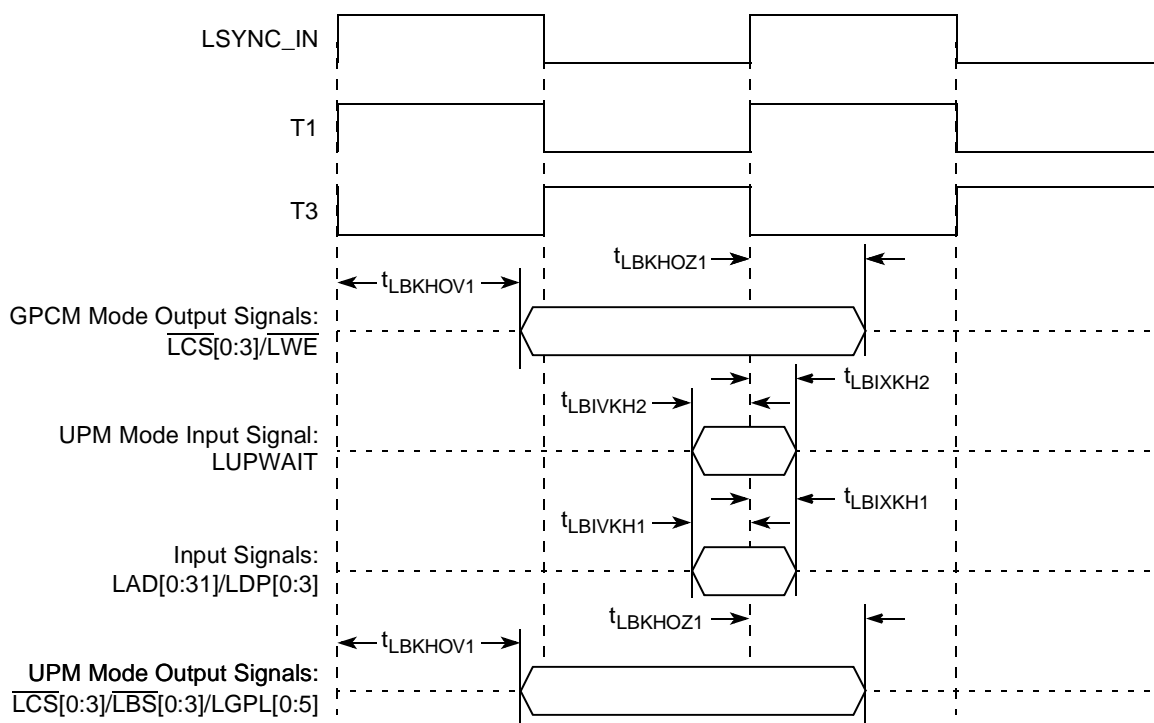


Figure 22. Local Bus Signals, GPCM/UPM Signals for LCCR[CLKDIV] = 2 (DLL Enabled)

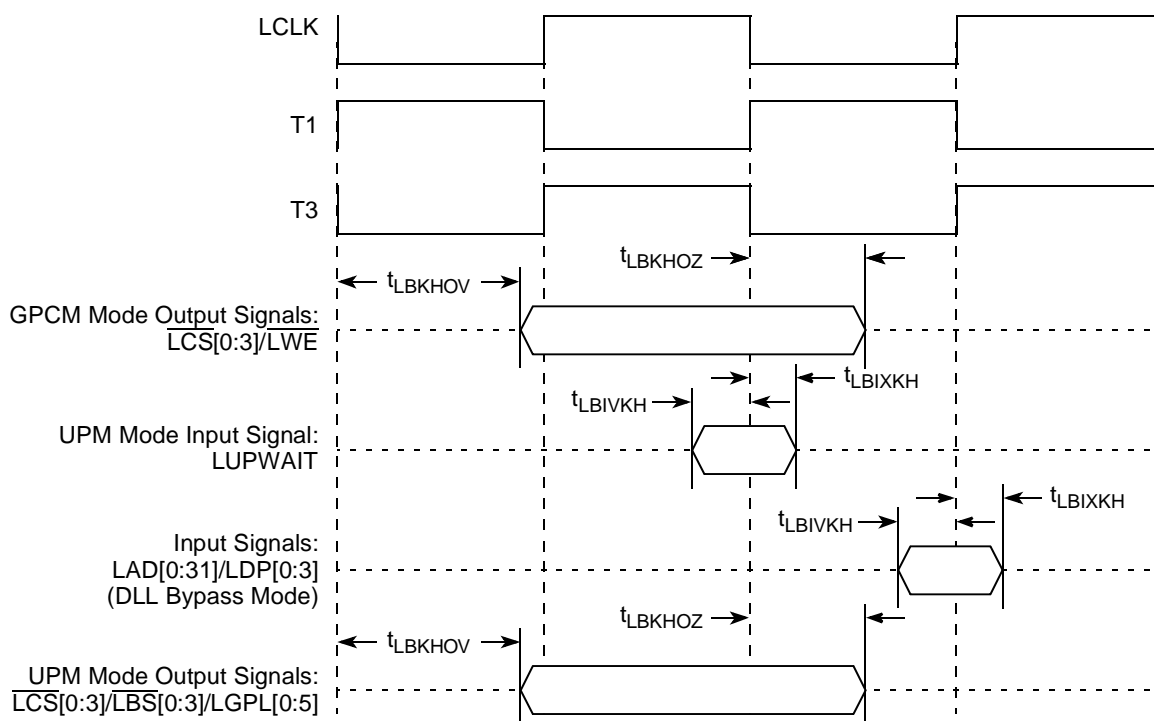


Figure 23. Local Bus Signals, GPCM/UPM Signals for LCCR[CLKDIV] = 2 (DLL Bypass Mode)

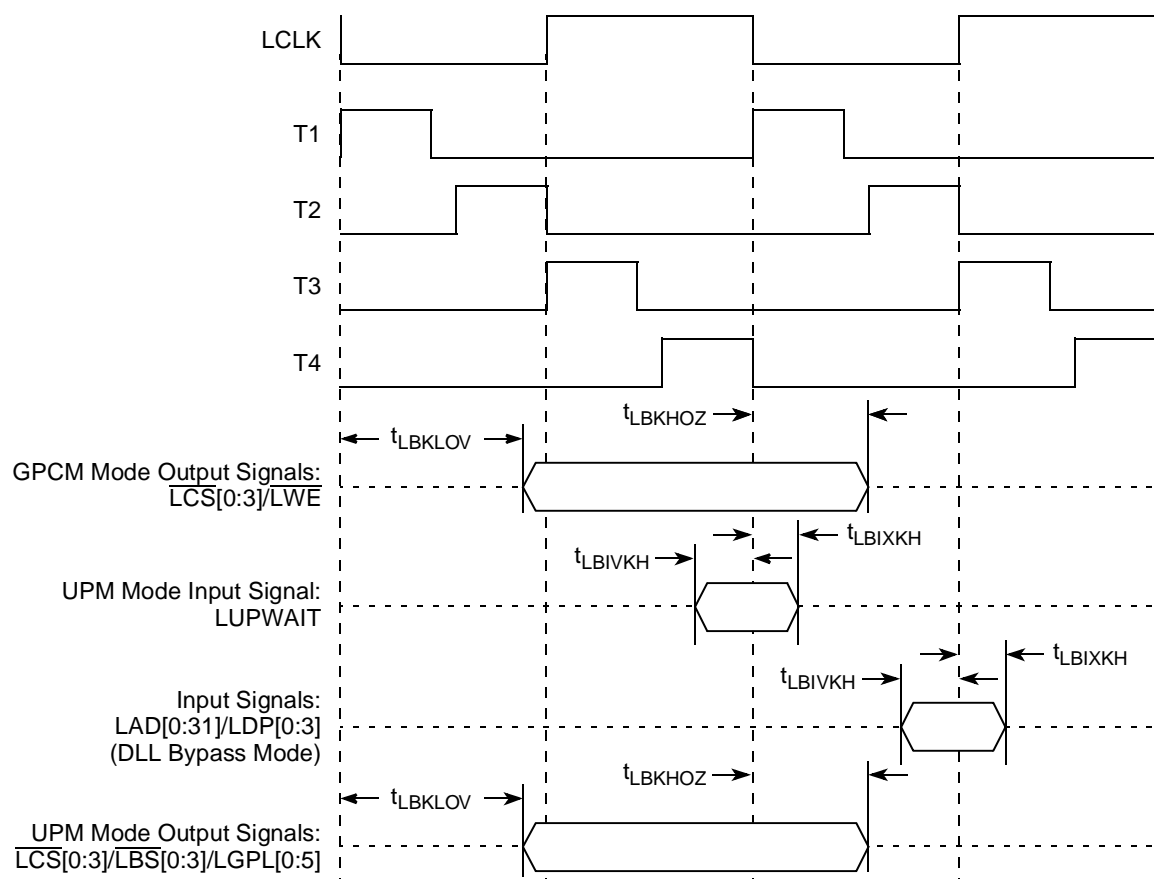


Figure 24. Local Bus Signals, GPCM/UPM Signals for LCCR[CLKDIV] = 4 (DLL Bypass Mode)

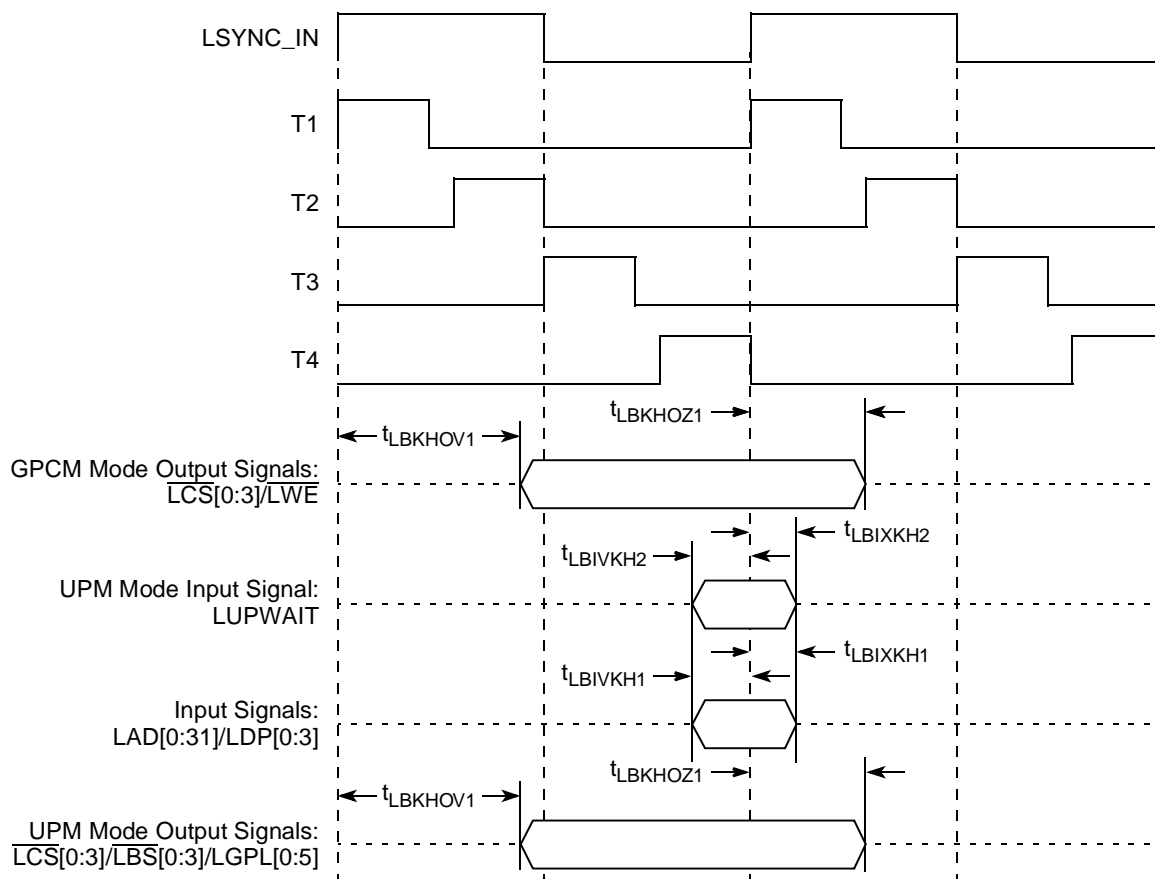


Figure 25. Local Bus Signals, GPCM/UPM Signals for LCCR[CLKDIV] = 4 (DLL Enabled)

Table 51. MPC8347E (TBGA) Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
MECC[0:4]/MSRCID[0:4]	W4, W3, Y3, AA6, T1	I/O	GV _{DD}	
MECC[5]/MDVAL	U1	I/O	GV _{DD}	
MECC[6:7]	Y1, Y6	I/O	GV _{DD}	
MDM[0:8]	B1, F1, K1, R4, AD4, AJ1, AP3, AP7, Y4	O	GV _{DD}	
MDQS[0:8]	B2, F5, J1, P2, AC1, AJ2, AN4, AL8, W2	I/O	GV _{DD}	
MBA[0:1]	AD1, AA5	O	GV _{DD}	
MA[0:14]	W1, U4, T3, R3, P1, M1, N1, L3, L1, K2, Y2, K3, J3, AP2, AN6	O	GV _{DD}	
$\overline{\text{MWE}}$	AF1	O	GV _{DD}	
$\overline{\text{MRAS}}$	AF4	O	GV _{DD}	
$\overline{\text{MCAS}}$	AG3	O	GV _{DD}	
$\overline{\text{MCS}}$ [0:3]	AG2, AG1, AK1, AL4	O	GV _{DD}	
MCKE[0:1]	H3, G1	O	GV _{DD}	3
MCK[0:5]	U2, F4, AM3, V3, F2, AN3	O	GV _{DD}	
$\overline{\text{MCK}}$ [0:5]	U3, E3, AN2, V4, E1, AM4	O	GV _{DD}	
Pins Reserved for Future DDR2 (They should be left unconnected for MPC8347)				
MODT[0:3]	AH3, AJ5, AH1, AJ4	—	—	
MBA[2]	H4	—	—	
SPARE1	AA1	—	—	8
SPARE2	AB1	—	—	6
Local Bus Controller Interface				
LAD[0:31]	AM13, AP13, AL14, AM14, AN14, AP14, AK15, AJ15, AM15, AN15, AP15, AM16, AL16, AN16, AP16, AL17, AM17, AP17, AK17, AP18, AL18, AM18, AN18, AP19, AN19, AM19, AP20, AK19, AN20, AL20, AP21, AN21	I/O	OV _{DD}	
LDP[0]/CKSTOP_OUT	AM21	I/O	OV _{DD}	
LDP[1]/CKSTOP_IN	AP22	I/O	OV _{DD}	
LDP[2]	AN22	I/O	OV _{DD}	
LDP[3]	AM22	I/O	OV _{DD}	
LA[27:31]	AK21, AP23, AN23, AP24, AK22	O	OV _{DD}	
$\overline{\text{LCS}}$ [0:3]	AN24, AL23, AP25, AN25	O	OV _{DD}	
$\overline{\text{LWE}}$ [0:3]/LSDDQM[0:3]/ $\overline{\text{LBS}}$ [0:3]	AK23, AP26, AL24, AM25	O	OV _{DD}	

Table 51. MPC8347E (TBGA) Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
DUART				
UART_SOUT[1:2]/MSRCID[0:1]/LSRCID[0:1]	AK27, AN29	O	OV _{DD}	
UART_SIN[1:2]/MSRCID[2:3]/LSRCID[2:3]	AL28, AM29	I/O	OV _{DD}	
UART_CTS[1]/MSRCID4/LSRCID4	AP30	I/O	OV _{DD}	
UART_CTS[2]/MDVAL/ LDVAL	AN30	I/O	OV _{DD}	
UART_RTS[1:2]	AP31, AM30	O	OV _{DD}	
I²C interface				
IIC1_SDA	AK29	I/O	OV _{DD}	2
IIC1_SCL	AP32	I/O	OV _{DD}	2
IIC2_SDA	AN31	I/O	OV _{DD}	2
IIC2_SCL	AM31	I/O	OV _{DD}	2
SPI				
SPIMOSI	AN32	I/O	OV _{DD}	
SPIMISO	AP33	I/O	OV _{DD}	
SPICLK	AK30	I/O	OV _{DD}	
SPISEL	AL31	I	OV _{DD}	
Clocks				
PCI_CLK_OUT[0:4]	AN9, AP9, AM10, AN10, AJ11	O	OV _{DD}	
PCI_SYNC_IN/PCI_CLOCK	AK12	I	OV _{DD}	
PCI_SYNC_OUT	AP11	O	OV _{DD}	3
RTC/PIT_CLOCK	AM32	I	OV _{DD}	
CLKIN	AM9	I	OV _{DD}	
JTAG				
TCK	E20	I	OV _{DD}	
TDI	F20	I	OV _{DD}	4
TDO	B20	O	OV _{DD}	3
TMS	A20	I	OV _{DD}	4
TRST	B19	I	OV _{DD}	4
Test				
TEST	D22	I	OV _{DD}	6
TEST_SEL	AL13	I	OV _{DD}	7
PMC				
QUIESCE	A18	O	OV _{DD}	

Table 51. MPC8347E (TBGA) Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
System Control				
$\overline{\text{PORESET}}$	C18	I	OV_{DD}	
$\overline{\text{HRESET}}$	B18	I/O	OV_{DD}	1
$\overline{\text{SRESET}}$	D18	I/O	OV_{DD}	2
Thermal Management				
THERM0	K32	I	—	9
Power and Ground Signals				
AV_{DD1}	L31	Power for e300 PLL (1.2 V)	AV_{DD1}	
AV_{DD2}	AP12	Power for system PLL (1.2 V)	AV_{DD2}	
AV_{DD3}	AE1	Power for DDR DLL (1.2 V)	AV_{DD3}	
AV_{DD4}	AJ13	Power for LBIU DLL (1.2 V)	AV_{DD4}	
GND	A1, A34, C1, C7, C10, C11, C15, C23, C25, C28, D1, D8, D20, D30, E7, E13, E15, E17, E18, E21, E23, E25, E32, F6, F19, F27, F30, F34, G31, H5, J4, J34, K30, L5, M2, M5, M30, M33, N3, N5, P30, R5, R32, T5, T30, U6, U29, U33, V2, V5, V30, W6, W30, Y30, AA2, AA30, AB2, AB6, AB30, AC3, AC6, AD31, AE5, AF2, AF5, AF31, AG30, AG31, AH4, AJ3, AJ19, AJ22, AK7, AK13, AK14, AK16, AK18, AK20, AK25, AK28, AL3, AL5, AL10, AL12, AL22, AL27, AM1, AM6, AM7, AN12, AN17, AN34, AP1, AP8, AP34	—	—	
GV_{DD}	A2, E2, G5, G6, J5, K4, K5, L4, N4, P5, R6, T6, U5, V1, W5, Y5, AA4, AB3, AC4, AD5, AF3, AG5, AH2, AH5, AH6, AJ6, AK6, AK8, AK9, AL6	Power for DDR DRAM I/O voltage (2.5 V)	GV_{DD}	
LV_{DD1}	C9, D11	Power for three-speed Ethernet #1 and for Ethernet management interface I/O (2.5 V, 3.3 V)	LV_{DD1}	

Table 52. MPC8347E (PBGA) Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
MVREF1	AF19	I	DDR reference voltage	
MVREF2	AE10	I	DDR reference voltage	
No Connection				
NC	V1, V2, V5			

Notes:

1. This pin is an open-drain signal. A weak pull-up resistor (1 k Ω) should be placed on this pin to OV_{DD}.
2. This pin is an open-drain signal. A weak pull-up resistor (2–10 k Ω) should be placed on this pin to OV_{DD}.
3. During reset, this output is actively driven rather than three-stated.
4. These JTAG pins have weak internal pull-up P-FETs that are always enabled.
5. This pin should have a weak pull-up if the chip is in PCI host mode. Follow the PCI specifications.
6. This pin must always be tied to GND.
7. This pin must always be left not connected.
8. Thermal sensitive resistor.
9. It is recommended that MDIC0 be tied to GRD using an 18 Ω resistor and MDIC1 be tied to DDR power using an 18 Ω resistor.
10. TSEC1_TXD[3] is required an external pull-up resistor. For proper functionality of the device, this pin must be pulled up or actively driven high during a hard reset. No external pull-down resistors are allowed to be attached to this net.

19.1 System PLL Configuration

The system PLL is controlled by the RCWL[SPMF] parameter. [Table 56](#) shows the multiplication factor encodings for the system PLL.

Table 56. System PLL Multiplication Factors

RCWL[SPMF]	System PLL Multiplication Factor
0000	× 16
0001	Reserved
0010	× 2
0011	× 3
0100	× 4
0101	× 5
0110	× 6
0111	× 7
1000	× 8
1001	× 9
1010	× 10
1011	× 11
1100	× 12
1101	× 13
1110	× 14
1111	× 15

As described in [Section 19, “Clocking,”](#) the LBIUCM, DDRCM, and SPMF parameters in the reset configuration word low and the CFG_CLKIN_DIV configuration input signal select the ratio between the primary clock input (CLKIN or PCI_CLK) and the internal coherent system bus clock (*csb_clk*). [Table 57](#) and [Table 58](#) show the expected frequency values for the CSB frequency for select *csb_clk* to CLKIN/PCI_SYNC_IN ratios.

20 Thermal

This section describes the thermal specifications of the MPC8347E.

20.1 Thermal Characteristics

Table 61 provides the package thermal characteristics for the 672 35 × 35 mm TBGA of the MPC8347E.

Table 61. Package Thermal Characteristics for TBGA

Characteristic	Symbol	Value	Unit	Notes
Junction-to-ambient natural convection on single-layer board (1s)	$R_{\theta JA}$	14	°C/W	1, 2
Junction-to-ambient natural convection on four-layer board (2s2p)	$R_{\theta JMA}$	11	°C/W	1, 3
Junction-to-ambient (@ 200 ft/min) on single-layer board (1s)	$R_{\theta JMA}$	11	°C/W	1, 3
Junction-to-ambient (@ 200 ft/min) on four-layer board (2s2p)	$R_{\theta JMA}$	8	°C/W	1, 3
Junction-to-ambient (@ 2 m/s) on single-layer board (1s)	$R_{\theta JMA}$	9	°C/W	1, 3
Junction-to-ambient (@ 2 m/s) on four-layer board (2s2p)	$R_{\theta JMA}$	7	°C/W	1, 3
Junction-to-board thermal	$R_{\theta JB}$	3.8	°C/W	4
Junction-to-case thermal	$R_{\theta JC}$	1.7	°C/W	5
Junction-to-package natural convection on top	Ψ_{JT}	1	°C/W	6

Notes:

1. Junction temperature is a function of die size, on-chip power dissipation, package thermal resistance, mounting site (board) temperature, ambient temperature, air flow, power dissipation of other components on the board, and board thermal resistance.
2. Per SEMI G38-87 and JEDEC JESD51-2 with the single-layer board horizontal.
3. Per JEDEC JESD51-6 with the board horizontal, 1 m/s is approximately equal to 200 linear feet per minute (LFM).
4. Thermal resistance between the die and the printed-circuit board per JEDEC JESD51-8. Board temperature is measured on the top surface of the board near the package.
5. Thermal resistance between the die and the case top surface as measured by the cold plate method (MIL SPEC-883 Method 1012.1).
6. Thermal characterization parameter indicating the temperature difference between package top and the junction temperature per JEDEC JESD51-2. When Greek letters are not available, the thermal characterization parameter is written as Psi-JT.

Table 62 provides the package thermal characteristics for the 620 29 × 29 mm PBGA of the MPC8347E.

Table 62. Package Thermal Characteristics for PBGA

Characteristic	Symbol	Value	Unit	Notes
Junction-to-ambient natural convection on single-layer board (1s)	$R_{\theta JA}$	21	°C/W	1, 2
Junction-to-ambient natural convection on four-layer board (2s2p)	$R_{\theta JMA}$	15	°C/W	1, 3
Junction-to-ambient (@ 200 ft/min) on single-layer board (1s)	$R_{\theta JMA}$	17	°C/W	1, 3
Junction-to-ambient (@ 200 ft/min) on four-layer board (2s2p)	$R_{\theta JMA}$	12	°C/W	1, 3
Junction-to-board thermal	$R_{\theta JB}$	6	°C/W	4

Table 62. Package Thermal Characteristics for PBGA (continued)

Characteristic	Symbol	Value	Unit	Notes
Junction-to-case thermal	$R_{\theta JC}$	5	°C/W	5
Junction-to-package natural convection on top	Ψ_{JT}	5	°C/W	6

Notes

1. Junction temperature is a function of die size, on-chip power dissipation, package thermal resistance, mounting site (board) temperature, ambient temperature, air flow, power dissipation of other components on the board, and board thermal resistance.
2. Per SEMI G38-87 and JEDEC JESD51-2 with the single-layer board horizontal.
3. Per JEDEC JESD51-6 with the board horizontal.
4. Thermal resistance between the die and the printed-circuit board per JEDEC JESD51-8. Board temperature is measured on the top surface of the board near the package.
5. Thermal resistance between the die and the case top surface as measured by the cold plate method (MIL SPEC-883 Method 1012.1).
6. Thermal characterization parameter indicating the temperature difference between package top and the junction temperature per JEDEC JESD51-2. When Greek letters are not available, the thermal characterization parameter is written as Psi-JT.

20.2 Thermal Management Information

For the following sections, $P_D = (V_{DD} \times I_{DD}) + P_{I/O}$ where $P_{I/O}$ is the power dissipation of the I/O drivers. See [Table 5](#) for I/O power dissipation values.

20.2.1 Estimation of Junction Temperature with Junction-to-Ambient Thermal Resistance

An estimation of the chip junction temperature, T_J , can be obtained from the equation:

$$T_J = T_A + (R_{\theta JA} \times P_D)$$

where:

T_J = junction temperature (°C)

T_A = ambient temperature for the package (°C)

$R_{\theta JA}$ = junction-to-ambient thermal resistance (°C/W)

P_D = power dissipation in the package (W)

The junction-to-ambient thermal resistance is an industry-standard value that provides a quick and easy estimation of thermal performance. Generally, the value obtained on a single-layer board is appropriate for a tightly packed printed-circuit board. The value obtained on the board with the internal planes is usually appropriate if the board has low power dissipation and the components are well separated. Test cases have demonstrated that errors of a factor of two (in the quantity $T_J - T_A$) are possible.

20.2.2 Estimation of Junction Temperature with Junction-to-Board Thermal Resistance

The thermal performance of a device cannot be adequately predicted from the junction-to-ambient thermal resistance. The thermal performance of any component is strongly dependent on the power dissipation of surrounding components. In addition, the ambient temperature varies widely within the application. For

Tyco Electronics Chip Coolers™ P.O. Box 3668 Harrisburg, PA 17105-3668 Internet: www.chipcoolers.com	800-522-2800
Wakefield Engineering 33 Bridge St. Pelham, NH 03076 Internet: www.wakefield.com	603-635-5102

Interface material vendors include the following:

Chomerics, Inc. 77 Dragon Ct. Woburn, MA 01801 Internet: www.chomerics.com	781-935-4850
Dow-Corning Corporation Dow-Corning Electronic Materials P.O. Box 994 Midland, MI 48686-0997 Internet: www.dowcorning.com	800-248-2481
Shin-Etsu MicroSi, Inc. 10028 S. 51st St. Phoenix, AZ 85044 Internet: www.microsi.com	888-642-7674
The Bergquist Company 18930 West 78th St. Chanhassen, MN 55317 Internet: www.bergquistcompany.com	800-347-4572

20.3 Heat Sink Attachment

When heat sinks are attached, an interface material is required, preferably thermal grease and a spring clip. The spring clip should connect to the printed-circuit board, either to the board itself, to hooks soldered to the board, or to a plastic stiffener. Avoid attachment forces that can lift the edge of the package or peel the package from the board. Such peeling forces reduce the solder joint lifetime of the package. The recommended maximum force on the top of the package is 10 lb force (4.5 kg force). Any adhesive attachment should attach to painted or plastic surfaces, and its performance should be verified under the application requirements.

20.3.1 Experimental Determination of the Junction Temperature with a Heat Sink

When a heat sink is used, the junction temperature is determined from a thermocouple inserted at the interface between the case of the package and the interface material. A clearance slot or hole is normally

22 Document Revision History

Table 66 provides a revision history of this document.

Table 66. Document Revision History

Revision	Date	Substantive Change(s)
11	2/2009	<p>In Section 21.1, "System Clocking," removed "(AVDD1)" and "(AVDD2)" from bulleted list.</p> <p>In Section 21.2, "PLL Power Supply Filtering," in the second paragraph, changed "provide five independent filter circuits," and "the five AVDD pins" to provide four independent filter circuits," and "the four AVDD pins."</p> <p>In Table 35, removed row for rise time (t_{12CR}). Removed minimum value of t_{12CF}. Added note 5 stating that the device does not follow the I2C-BUS Specifications version 2.1 regarding the t_{12CF} AC parameter.</p> <p>In Table 54, corrected the max csb_clk to 266 MHz.</p> <p>In Table 60, added PLL configurations 903, 923, A03, A23, and 503 for 533 MHz</p> <p>In Table 35, corrected t_{LBKHOV} parametr to t_{LBKLOV} (output data is driven on falling edge of clock in DLL bypass mode). Similarly, made the same correction to Figure 21, Figure 23, and Figure 24 for output signals.</p> <p>Added Figure 1 and Figure 4.</p> <p>In Table 9.2, clarified that AC table is for ULPI only.</p> <p>Added footnote 4 to Table 67.</p> <p>In Table 67, updated note 1 to say the following: "For temperature range = C, processor frequency is up to 667(TBGA) with a platform frequency of 333 and limited to 400 (PBGA) with a platform frequency of 266."</p> <p>Added footnote 10 and 11 to Table 51 and Table 52.</p> <p>In Table 51, Table 52, updated note 11 to say the following: "SEC1_TXD[3] is required an external pull-up resistor. For proper functionality of the device, this pin must be pulled up or actively driven high during a hard reset. No external pull-down resistors are allowed to be attached to this net."</p> <p>Added footnote 6 to Table 7.</p> <p>In Table 7, updated the note 6 to say the following: "The Spread spectrum clocking. Is allowed with 1% input frequency down-spread at maximum 50KHz modulation rate regardless of input frequency."</p> <p>In 8.1.1, removed the note "The potential applied to the input of a GMII, MII, TBI, RGMII, or RTBI receiver may exceed the potential of the receiver power supply (that is, a RGMII driver powered from a 3.6 V supply driving VOH into a RGMII receiver powered from a 2.5-V supply). Tolerance for dissimilar RGMII driver and receiver supply potentials is implicit in these specifications."</p>
10	4/2007	<p>In Table 3, "Output Drive Capability," changed the values in the Output Impedance column and added USB to the seventh row.</p> <p>In Table 54, "Operating Frequencies for TBGA," added column for 400 MHz.</p> <p>In Section 21.7, "Pull-Up Resistor Requirements," deleted last two paragraphs and after first paragraph, added a new paragraph.</p> <p>Deleted Section 21.8, "JTAG Configuration Signals," and Figure 43, "JTAG Interface Connection."</p>
9	3/2007	<p>In Table 54, "Operating Frequencies for TBGA," in the 'Coherent system bus frequency (csb_clk)' row, changed the value in the 533 MHz column to 100–333.</p> <p>In Table 60, "Suggested PLL Configurations," under the subhead, '33 MHz CLKIN/PCI_CLK Options,' added row A03 between Ref. No. 724 and 804. Under the subhead '66 MHz CLKIN/PCI_CLK Options,' added row 503 between Ref. No. 305 and 404. For Ref. No. 306, changed the CORE PLL value to 0000110.</p> <p>In Section 23, "Ordering Information," replaced first paragraph and added a note.</p> <p>In Section 23.1, "Part Numbers Fully Addressed by This Document," replaced first paragraph.</p>

Table 66. Document Revision History (continued)

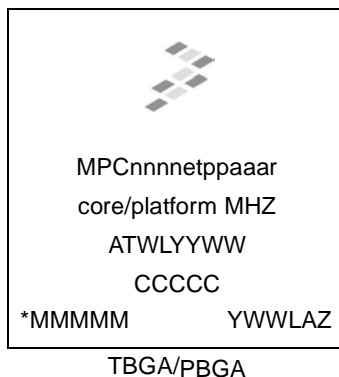
Revision	Date	Substantive Change(s)
1	4/2005	Table 1: Addition of note 1 Table 48: Addition of Therm0 (K32) Table 49: Addition of Therm0 (B15)
0	4/2005	Initial release.

Table 68. SVR Settings (continued)

MPC8347E	PBGA	8054_0010
MPC8347	PBGA	8055_0010

23.2 Part Marking

Parts are marked as in the example shown in [Figure 44](#).



Notes:

ATWLYYWW is the traceability code.

CCCCC is the country code.

MMMMM is the mask number.

YWWLAZ is the assembly traceability code.

Figure 44. Freescale Part Marking for TBGA or PBGA Devices